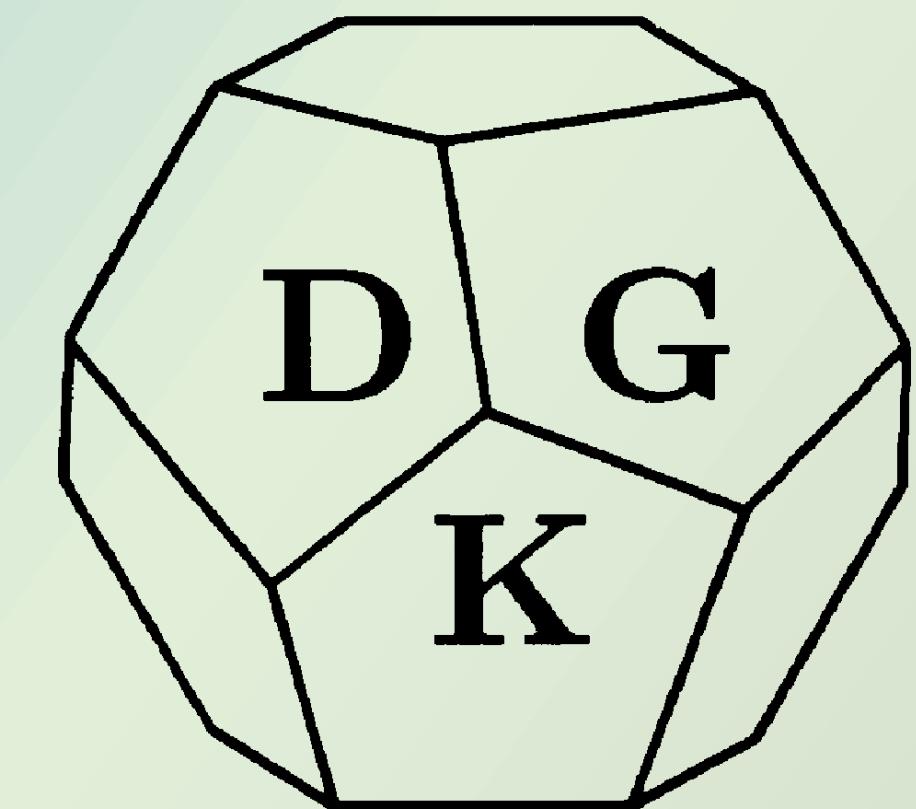


Closing Some Gaps of Knowledge: Single Crystals of $\text{Pr}_2\text{O}[\text{SiO}_4]$ and $\text{Sm}_2\text{O}[\text{SiO}_4]$ with the A-Type Structure

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Introduction

Syntheses with lanthanoid metals in glassy silica ampoules often tend to yield oxosilicates as by-products. Thus, the two presented silicates $\text{Pr}_2\text{O}[\text{SiO}_4]$ and $\text{Sm}_2\text{O}[\text{SiO}_4]$ were also obtained from different reactions including the elemental lanthanoids, but with other target compounds. Both crystallize isostructurally to the $\text{Ln}_2\text{O}[\text{SiO}_4]$ series with $\text{Ln} = \text{La}, \text{Nd}, \text{Eu}, \text{Gd}, \text{Ho} - \text{Tm}$ and $\text{Lu}^{[1-6]}$ in the monoclinic space group $P2_1/c$ with the lattice parameters $a = 925.49(8)$ pm, $b = 717.19(6)$ pm, $c = 692.06(5)$ pm, $\beta = 108.382(3)^\circ$ for $\text{Pr}_2\text{O}[\text{SiO}_4]_2$ (CSD-2127743) and $a = 915.92(8)$ pm, $b = 717.19(6)$ pm, $c = 679.42(5)$ pm, $\beta = 107.825(3)^\circ$ for $\text{Sm}_2\text{O}[\text{SiO}_4]_2$ (CSD-2127807) adopting the $\text{Gd}_2\text{O}[\text{SiO}_4]_2^-$ - or A-type structure with $Z = 4$.

Atomic Positions and Equivalent Isotropic Displacement Parameters									Experimental Procedure	
$\text{Pr}_2\text{O}[\text{SiO}_4]$				$\text{Sm}_2\text{O}[\text{SiO}_4]$					Experimental Procedure	
Atom	Wyckoff site	x/a	y/b	z/c	$U_{\text{eq}}/\text{pm}^2$	x/a	y/b	z/c	$U_{\text{eq}}/\text{pm}^2$	
$\text{Ln}1$	4e	0.38805(7)	0.15075(9)	0.09143(9)	167(2)	0.38706(7)	0.14851(8)	0.08820(8)	147(2)	
$\text{Ln}2$	4e	0.01579(7)	0.12457(9)	0.23538(9)	157(2)	0.02097(7)	0.12454(8)	0.23477(8)	140(2)	
Si	4e	0.2988(4)	0.5825(5)	0.0420(5)	156(6)	0.2985(4)	0.5836(5)	0.0421(5)	147(6)	
O1	4e	0.2935(10)	0.0714(14)	0.3644(12)	194(17)	0.2935(10)	0.0722(13)	0.3598(12)	167(16)	
O2	4e	0.3659(10)	0.4617(12)	0.2509(12)	190(17)	0.3650(10)	0.4584(12)	0.2500(12)	194(18)	
O3	4e	0.8801(10)	0.3649(13)	0.0039(13)	198(19)	0.8822(10)	0.3635(11)	0.0060(13)	183(17)	
O4	4e	0.5926(10)	0.2528(14)	0.4468(13)	204(19)	0.5941(10)	0.2604(13)	0.4473(12)	233(19)	
O5	4e	0.1127(10)	0.3742(12)	0.4500(14)	191(17)	0.1139(10)	0.3775(11)	0.4506(13)	177(18)	

Crystallographic Data	$\text{Pr}_2\text{O}[\text{SiO}_4]$	$\text{Sm}_2\text{O}[\text{SiO}_4]$
Crystal system	monoclinic	
Space group	$P2_1/c$ (no. 14)	
Lattice parameters		
a/pm	925.49(8)	915.92(8)
b/pm	733.97(6)	717.09(6)
c/pm	692.06(5)	679.34(5)
$\beta/^\circ$	108.382(3)	107.815(3)
Number of formula units		$Z = 4$
Calculated density (D_x in g/cm^3)	5.805	6.392
Molar volume (V_m in cm^3/mol)	446.12	424.79
Diffractometer	$\kappa\text{-CCD}$ (Bruker-Nonius)	
Wavelength	Mo-K α : $\lambda = 71.07$ pm	
Diffractometer limit ($2\theta_{\text{max}}$ in deg)	65.83	56.62
Index range ($\pm h_{\text{max}}, \pm k_{\text{max}}, \pm l_{\text{max}}$)	13 / 11 / 10	12 / 9 / 9
Number of e^- per unit cell (F(000))	688	712
Absorption coefficient (μ in mm^{-1})	21.76	27.56
Number of collected / unique reflections	7503 / 1564	9487 / 1051
Data set residuals (R_{int} / R_o)	0.089 / 0.063	0.088 / 0.037
Structure residuals (R_1 / wR_2)	0.057 / 0.147	0.044 / 0.102
Goodness of Fit ($GooF$)	1.108	1.096
Residual electron density (max. / min.)	3.16 / -3.49	2.37 / -2.40
Structure solution and refinement	Program package SHELX-97 [8]	

Literature

- [1] K. Fukuda, T. Iwata, E. Champion, *Powd. Diffrr.* **2006**, *21*, 300.
- [2] L. Leon-Reina, J. M. Porras-Vazquez, E. R. Losilla, L. Moreno-Real, M. A. G. Aranda, *J. Solid State Chem.* **2008**, *181*, 2501.
- [3] M. E. Bohem, Th. Schleid, *Z. Anorg. Allg. Chem.* **2016**, *642*, 1055.
- [4] Yu. I. Smolin, S. P. Tkachev, *Kristallografiya* **1969**, *14*, 22.
- [5] I. Hartenbach, S. F. Meier, J. Wontcheu, Th. Schleid, *Z. Anorg. Allg. Chem.* **2002**, *628*, 2907.
- [6] H. Müller-Bunz, Th. Schleid, *Z. Anorg. Allg. Chem.* **1999**, *625*, 613.
- [7] I. Hartenbach, Th. Schleid, *Z. Kristallogr.* **2005**, *220*, 206.
- [8] G. M. Sheldrick, *Acta Crystallogr.* **2008**, *A64*, 114.

Structure Description
The Ln^{3+} cations occupy two crystallographically different positions. $(\text{Ln}1)^{3+}$ resides in a distorted capped square hemiprism with 8+1 oxygen atoms, while $(\text{Ln}2)^{3+}$ centers a capped trigonal prism with seven of them. The lanthanoid-oxygen distances, namely $d(\text{Pr}-\text{O}) = 234 - 269$ pm and $d(\text{Sm}-\text{O}) = 231 - 259$ pm, fall into the usual range, when compared with similar praseodymium and samarium oxosilicates, such as apatite-type $\text{Ln}_{4.667}\text{O}[\text{SiO}_4]_3$ ($\text{Ln} = \text{Pr}$ and Sm)^[7]. Silicon is surrounded by a slightly distorted tetrahedron with four oxygen atoms as *ortho*-oxosilicate anion $[\text{SiO}_4]^{4-}$ with silicon-oxygen distances ranging from 159 to 166 pm, which remains isolated. The fifth oxygen atom works as an O^{2-} anion, which is coordinated by four Ln^{3+} cations as $[\text{O}\text{Ln}_4]^{10+}$ tetrahedron ($d(\text{O}-\text{Ln}) = 230 - 243$ pm). Their interconnection via edges and corners leads to ${}^2\{[\text{O}(\text{Ln}1)_{1/1}(\text{Ln}2)_{3/3}]^{4+}\}$ layers spreading out parallel to the (100) plane.

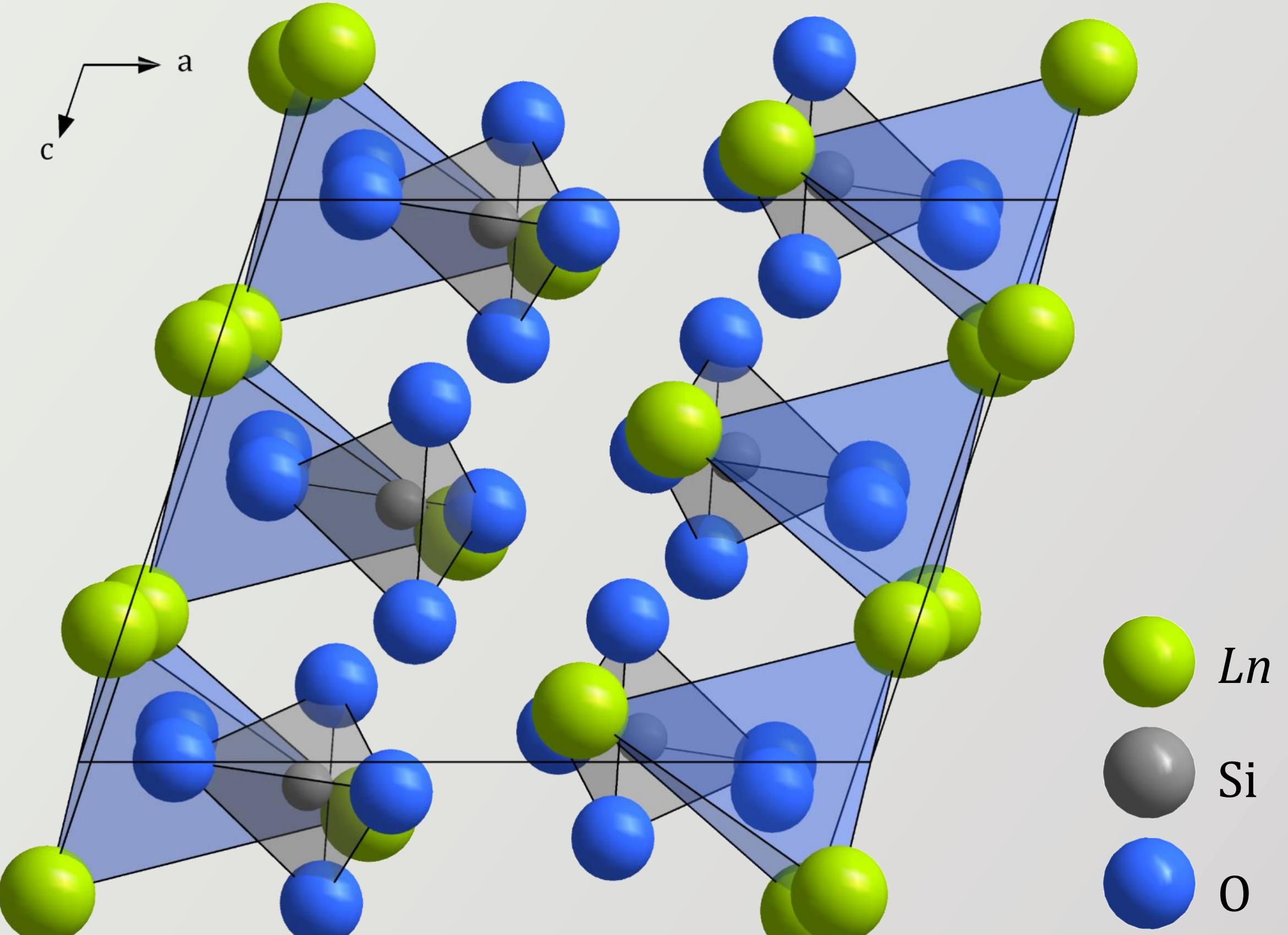


Figure 1. Projection of the monoclinic crystal structure of $\text{Ln}_2\text{O}[\text{SiO}_4]$ ($\text{Ln} = \text{Pr}$ and Sm) onto (010) showing the isolated $[\text{SiO}_4]^{4-}$ tetrahedra.

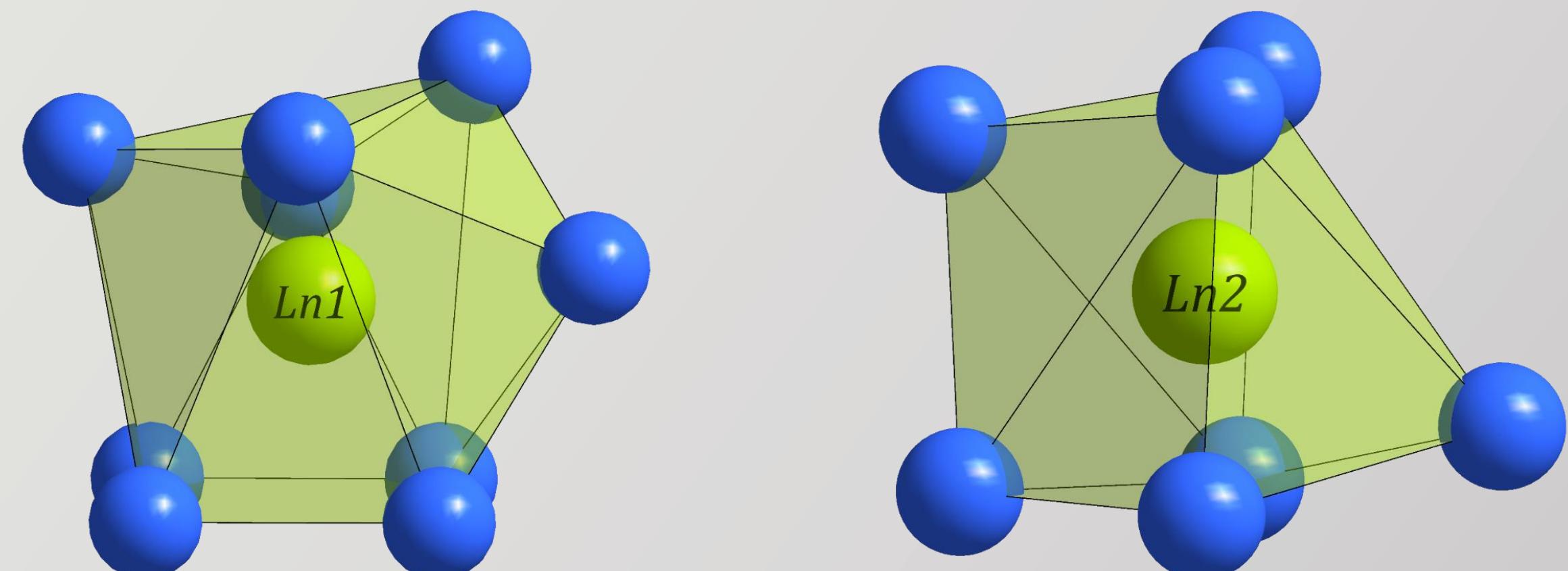


Figure 2. Anionic coordination polyhedra of the two crystallographically different Ln^{3+} cations in $\text{Pr}_2\text{O}[\text{SiO}_4]$ and $\text{Sm}_2\text{O}[\text{SiO}_4]$.